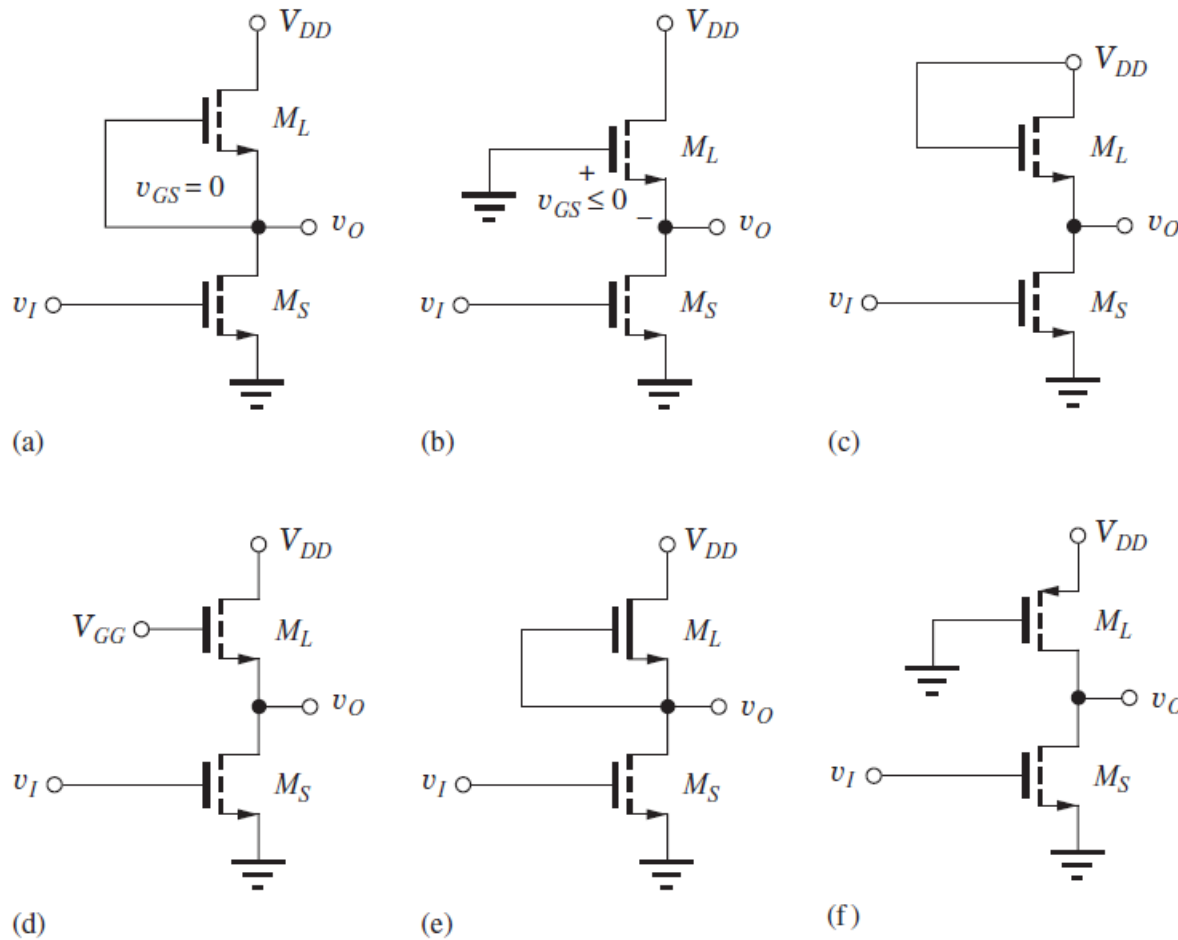


Announcements

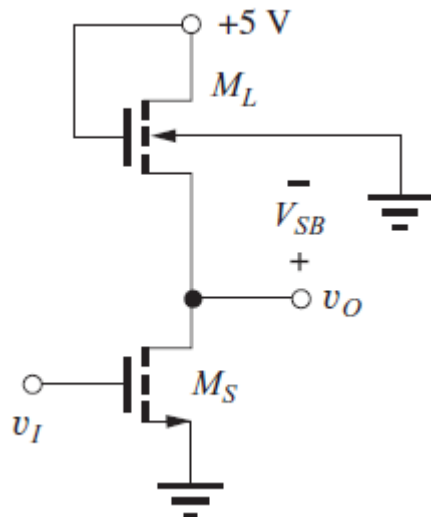
- Exam 2 in class on Monday 5/19
 - Chapters 4.1-4.6, 4.9-4.10, 6.1-6.2, and 6.4-6.8
 - MOSFET device behavior
 - MOSFETs in circuits and NMOS inverters/logic
 - HWs 4-6

Transistor alternatives to load resistor

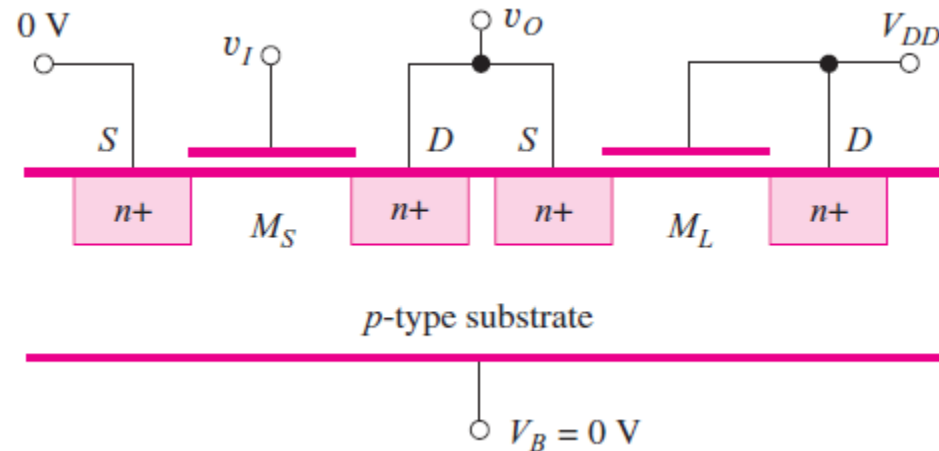


- (a,b) X
- c: saturated load ✓
- d: linear load ✓
- e: depletion-mode load ✓
- f: pseudo NMOS ✓

NMOS **saturated load** inverter



$$\begin{aligned} v_{GS} &= v_{DS}, V_{TN} > 0 \\ \Rightarrow v_{GS} - V_{TN} &< v_{DS} \\ \Rightarrow \text{Always in saturation} \end{aligned}$$

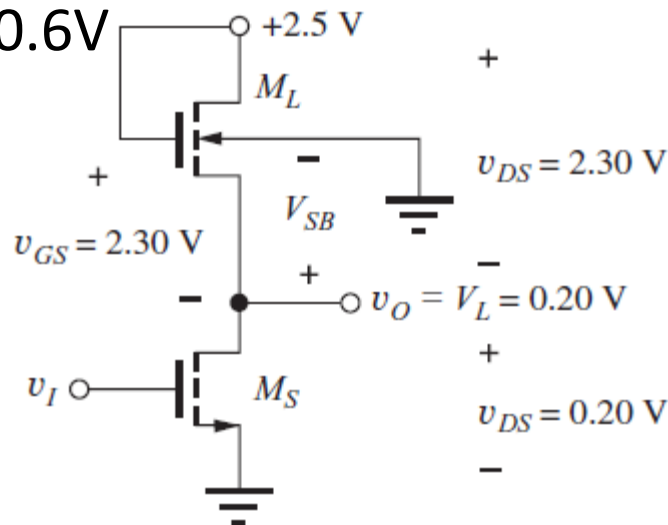


- Common substrate for load and switching device
- Body terminal connected to ground
 - $v_{SB} = 0$ for M_S
 - $v_{SB} \neq 0$ for M_L ! In fact, $v_{SB} = v_O$

Design of $\left(\frac{W}{L}\right)_L$ (Load transistor)

$$K_n' = 100 \mu\text{A}/\text{V}^2$$

$$V_{TO} = 0.6\text{V}$$



$$v_I = V_H, v_O = V_L$$

Current determined by
permissible power dissipation
of the NMOS, $P = V_{DD}I_{DD}$

$v_I = V_H$, M_S triode, M_L saturation

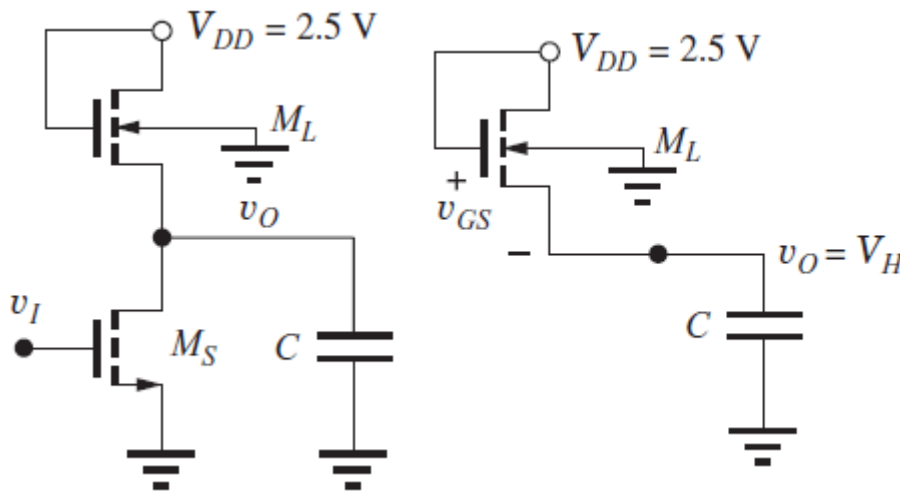
- Use the same conditions as before:
 $I_{DD} = 80 \mu\text{A}$, $V_{DD} = 2.5\text{V}$, $V_L = 0.20\text{V}$
- Saturation region equation for M_L :

$$i_D = K_n' \left(\frac{W}{L}\right)_L (v_{GS} - V_{TNL})^2$$

- $v_{GS} = V_{DD} - V_L = 2.3\text{V}$
- Body effect for M_L :
- $V_{TNL} = V_{TO} + \gamma(\sqrt{v_{SB} + 2\phi_F} - \sqrt{2\phi_F})$
- $v_{SB} = V_L = 0.2\text{V}$, $2\phi_F = 0.6\text{V}$, $V_{TO} = 0.6\text{V}$, $\gamma = 0.5\sqrt{\text{V}} \Rightarrow V_{TNL} = 0.66\text{V}$
- $\left(\frac{W}{L}\right)_L = \frac{2i_D}{K_n'(v_{GS} - V_{TNL})^2} = \frac{1}{1.68}$

Calculation of V_H

$v_I = V_L, v_O = V_H, M_S$ Cutoff

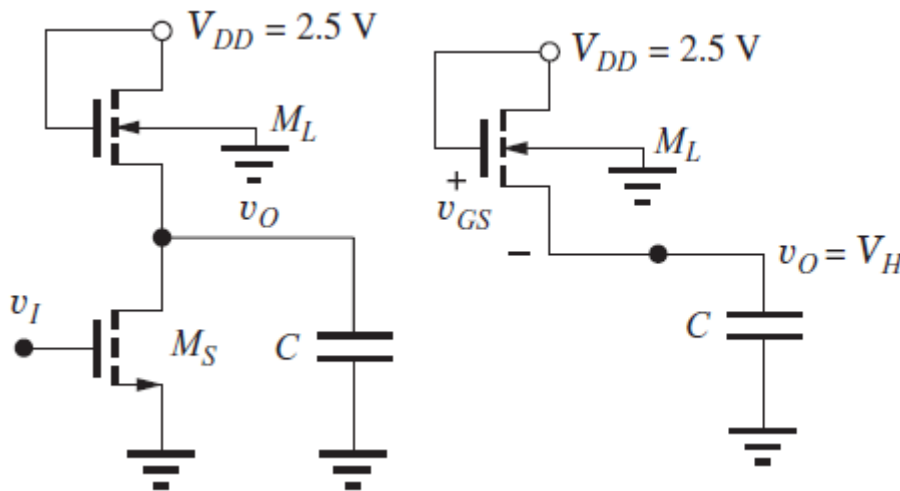


Imagine a capacitive load attached in parallel with M_S

- When $v_I = V_L$, M_S is cutoff, M_L saturated (on) and charging the capacitor.
- As capacitor gets charged,
 - v_O increases
 - v_{GS} for M_L decreases
- Charging stops when M_L turns off ($v_{GS} = V_{TNL}$), and
$$V_H = V_{DD} - v_{GS} = V_{DD} - V_{TNL}$$
- V_H reaches maximum of one V_T below V_{DD}
- Substantial degradation in V_H for the saturated load inverter!

Calculation of V_H

$v_I = V_L, v_O = V_H, M_S$ Cutoff



Imagine a capacitive load attached in parallel with M_S

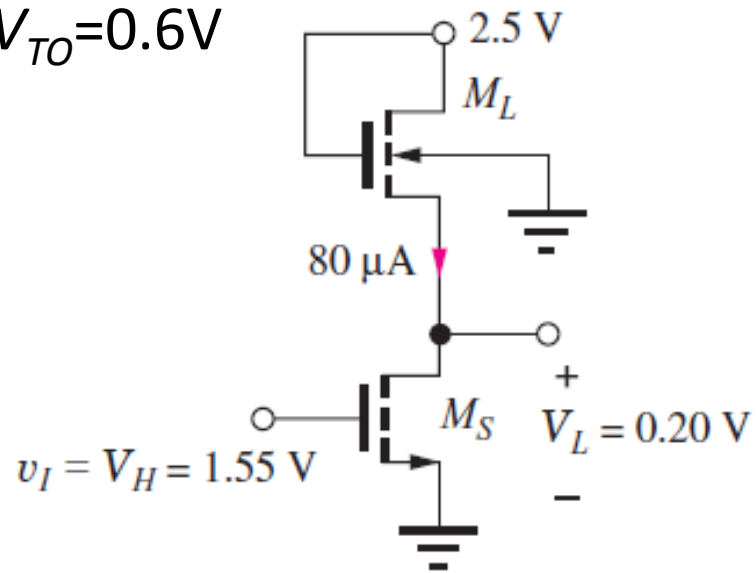
- $V_H = V_{DD} - V_{TNL}$
- Without Body effect,
 $V_H = 2.5 \text{ V} - 0.6 \text{ V} = 1.9 \text{ V}$
- Body effect makes the situation even worse!
- Use $v_{SB} = V_H$ and solve
 $V_{DD} - V_H = V_{TO} + \gamma(\sqrt{V_H + 2\phi_F} - \sqrt{2\phi_F})$
- We get

$$V_H = 1.55 \text{ V}$$

Design of $\left(\frac{W}{L}\right)_S$ (Switching transistor)

$$K_n' = 100 \mu\text{A}/\text{V}^2$$

$$V_{TO} = 0.6 \text{ V}$$



$$v_I = V_H, v_O = V_L$$

$v_I = V_H$, M_S triode, M_L saturation

- Use the same conditions as before:

$$I_{DD} = 80 \mu\text{A}, V_L = 0.20 \text{ V}$$

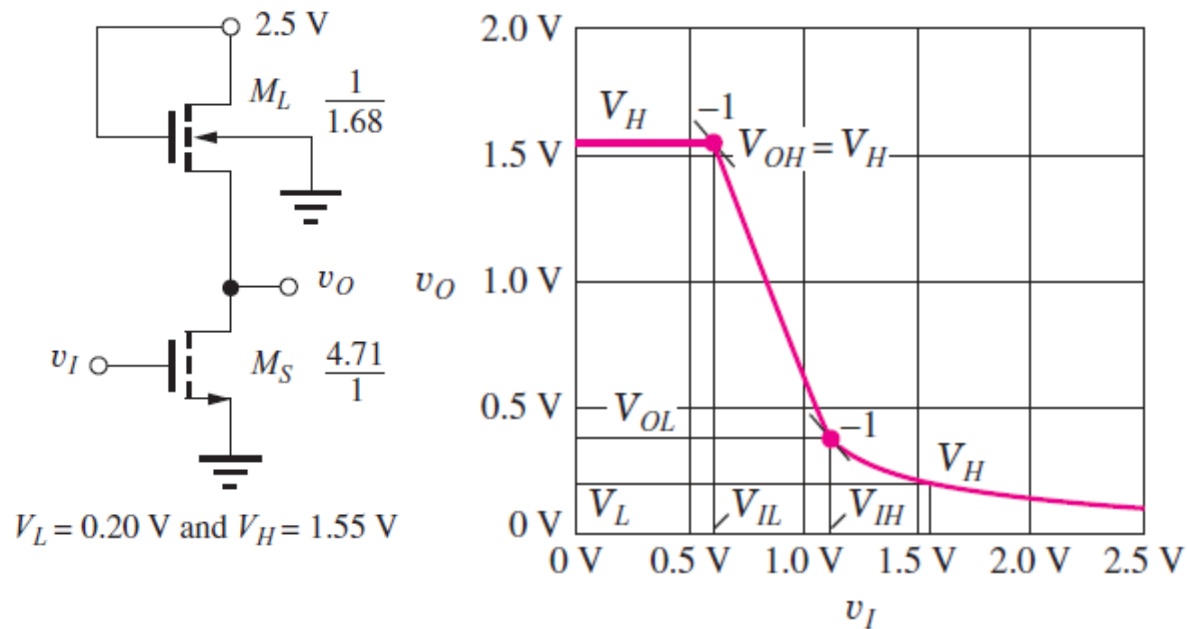
- Except $V_H = 1.55 \text{ V} \neq V_{DD}$!

- Triode region equation for M_S :

$$i_D = K_n' \left(\frac{W}{L}\right)_S \left(v_{GS} - V_{TNS} - \frac{v_{DS}}{2}\right) v_{DS}$$

- $v_{GS} = V_H = 1.55 \text{ V}$, $v_{DS} = V_L = 0.2 \text{ V}$, $V_{TNS} = 0.6 \text{ V} \Rightarrow \left(\frac{W}{L}\right)_S = \frac{4.71}{1}$

Noise margin analysis

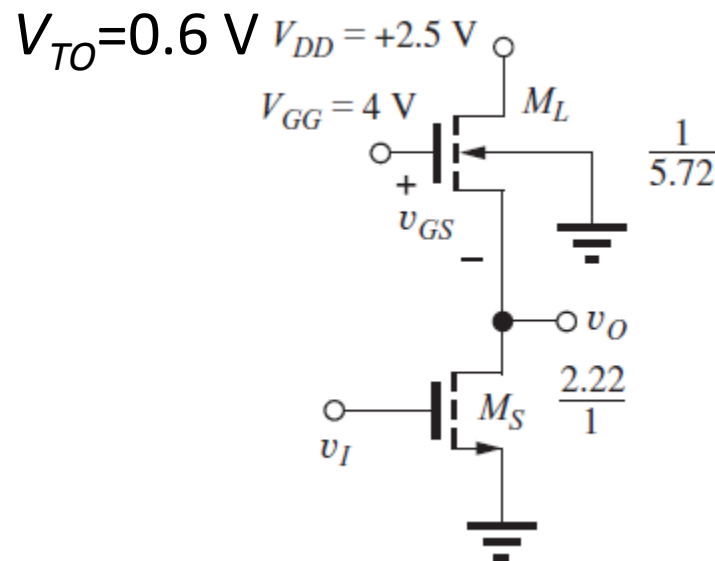


Completed inverter design and SPICE simulation of VTC for NMOS inverter with saturated load

- $V_{IL} = 0.6 \text{ V}$, $V_{OH} = 1.55 \text{ V}$
- $V_{IH} = 1.12 \text{ V}$, $V_{OL} = 0.38 \text{ V}$
- $NM_H = 0.43 \text{ V}$, $NM_L = 0.22 \text{ V}$
- NM_H is significantly reduced, NM_L is similar

NMOS **linear** load inverter

$$K_n' = 100 \mu\text{A}/\text{V}^2$$



Choose V_{GG} such that $V_{GG} > V_{DD} + V_{TNL}$
 M_L : Always in triode region

- For M_L :

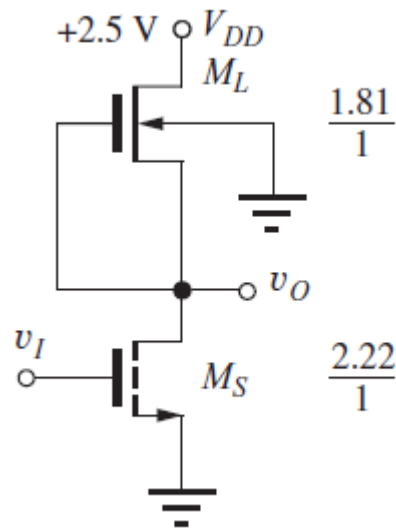
$$v_{GS} - V_{TNL} = V_{GG} - v_O - V_{TNL} \geq V_{DD} + V_{TNL} - v_O - V_{TNL} = V_{DD} - v_O = V_{DS} \Rightarrow \text{Always in triode (linear) region.}$$

- Body effect exists for M_L
 - $v_{SB} \neq 0$ for M_L ! In fact, $v_{SB} = v_O$

NMOS depletion-mode load inverter

$$K_n' = 100 \mu\text{A}/\text{V}^2$$

$$V_{TO} = -1 \text{ V}$$



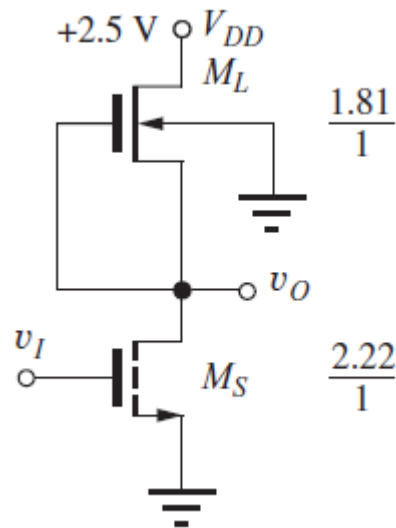
For M_L : $v_{GS} = 0, V_{TN} < 0$
 $\Rightarrow$ Always on
 (designed to be saturated)

- $v_I = V_L$, M_S is off, M_L conducts current until $v_{DS} = 0$ ($v_O = V_{DD}$), thus $V_H = V_{DD}$
- $v_I = V_H, v_O = V_L$, for M_L
 - $v_{GS} - V_{TNL} = -V_{TNL}$
 - $v_{DS} = v_{DD} - v_O$
 - As long as $v_{DD} - v_O > -V_{TNL}$, M_L in saturation
- Body effect exists for M_L
 - $v_{SB} \neq 0$ for M_L ! In fact, $v_{SB} = v_O$

Design of $\left(\frac{W}{L}\right)_S$ and $\left(\frac{W}{L}\right)_L$

$$K_n' = 100 \mu\text{A}/\text{V}^2$$

$$V_{TO} = -1 \text{ V}$$



For M_L : $v_{GS} = 0, V_{TN} < 0$
 $\Rightarrow$ Always on
 (designed to be saturated)

$v_I = V_H$, M_S triode, M_L saturation

• $I_{DD} = 80 \mu\text{A}, V_L = 0.20 \text{ V}, V_H = 2.5 \text{ V}$

• Saturation region equation for M_L :

$$i_D = \frac{K_n'}{2} \left(\frac{W}{L}\right)_L (0 - V_{TNL})^2$$

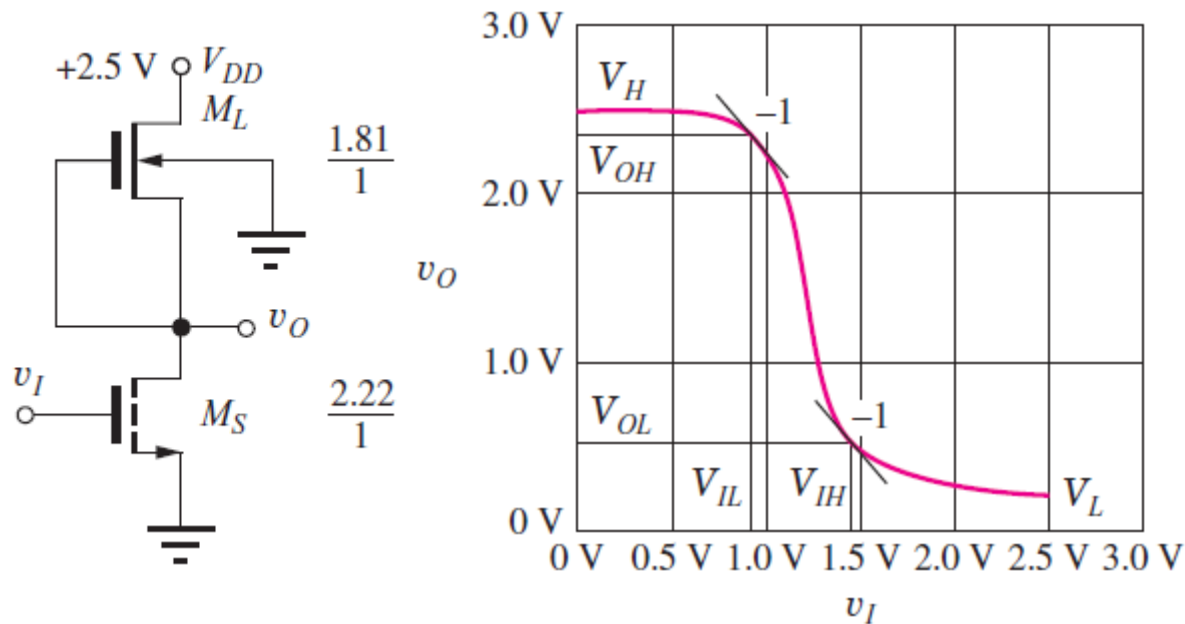
• Body effect for M_L :

• $V_{TNL} = V_{TO} + \gamma(\sqrt{V_L + 2\phi_F} - \sqrt{2\phi_F}) = -0.94 \text{ V}$

• This gives $\left(\frac{W}{L}\right)_L = \frac{1.81}{1}$

• For M_S , the same as in the resistive load case, thus $\left(\frac{W}{L}\right)_S = \frac{2.22}{1}$

Noise margin analysis



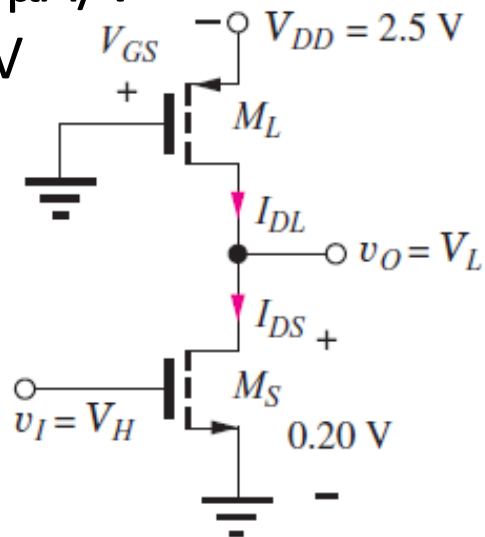
Completed inverter design and SPICE simulation of VTC for NMOS inverter with depletion-mode load

- $V_{IL} = 0.93 \text{ V}$, $V_{OH} = 2.35 \text{ V}$
- $V_{IH} = 1.45 \text{ V}$, $V_{OL} = 0.50 \text{ V}$
- $NM_H = 0.90 \text{ V}$, $NM_L = 0.43 \text{ V}$
- NM_H is high as in resistive load, NM_L is improved

Pseudo NMOS inverter

$$K_n' = 100 \mu\text{A}/\text{V}^2$$

$$V_{TO} = -1 \text{ V}$$



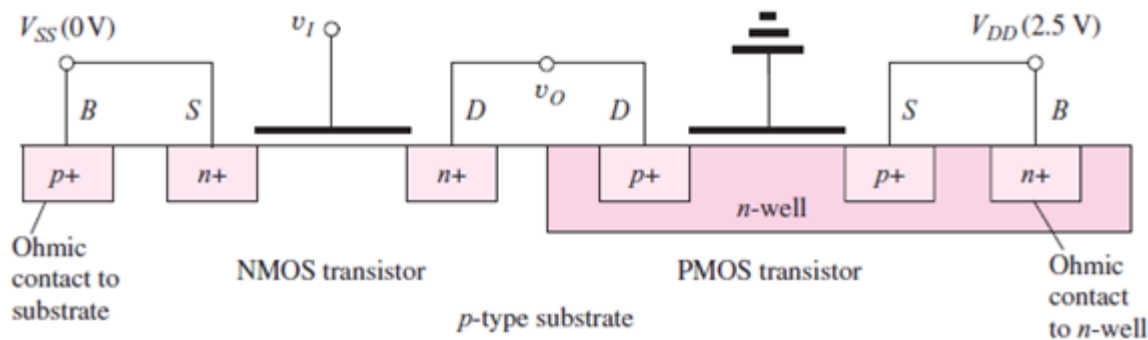
- For M_L :

$$V_{GS} < V_{TNL} \Rightarrow \text{On}$$

When $v_O = V_L$, $|V_{DS}| < |V_{GS} - V_{TN}| \Rightarrow \text{saturated}$

$$V_H = V_{DD} \Rightarrow \text{no degradation of } V_H$$

- No body effect for M_L !
 – Bulk and source are connected for M_L



NMOS Inverter Comparison

	Pros	Cons
Resistive Load	Simple	Takes too much area
Saturated Load	Simple	Degradation of V_H Poor speed
Linear Load	faster speed	Additional power supply
Depletion-mode load	Saves area Best Noise Margin High speed	Process complexity (Implant)
Pseudo NMOS	Smallest area Best speed	Process complexity (PMOS, Implant)